

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al.      Art Unit : Unknown  
Serial No. : New Divisional Application      Examiner : Unknown  
Filed : October 27, 2003  
Title : SEMICONDUCTOR INTEGRATED CIRCUIT AND FABRICATION  
METHOD THEREOF

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450


**INFORMATION DISCLOSURE STATEMENT**

Under 35 USC §120, this application relies on the earlier filing dates of application serial number 10/105,282, filed on March 26, 2002. The attached list of references were submitted to and/or cited by the Office in the prior applications and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: October 27, 2003

  
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(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
12732-097002Application No.  
New Divisional  
Application**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant  
Shunpei Yamazaki et al.Filing Date  
October 27, 2003Group Art Unit  
Unknown**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)

Substitute Form PTO-1449 (Modified)				U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 12732-097002		Application No. New Divisional Application	
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))						Applicant Shunpei Yamazaki et al.			
						Filing Date October 27, 2003		Group Art Unit Unknown	
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes    No		
	AAA	06-148685	05/27/1994	JAPAN			ABS		
	ABB	07-130652	05/19/1995	JAPAN			ABS		
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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
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	AHH	
	AII	
	AJJ	

Examiner Signature	Date Considered
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